

**Search Notes**

Application/Control No.

10/802,734

Examiner

Jim Vannucci

Applicant(s)/Patent under  
Reexamination

BEHFAR ET AL.

Art Unit

2828

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
etched gap, dbr, laser, facet	1/3/2005	JV